

ANTENNA

TEST REPORT

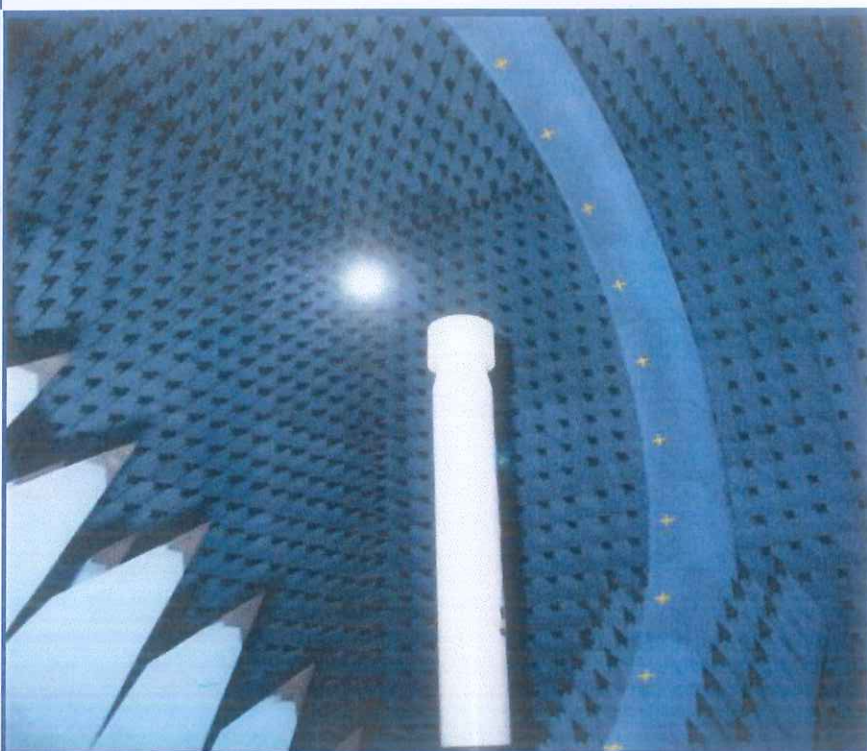
ISSUED BY
Shenzhen BALUN Technology Co., Ltd.



FOR
XMTZC04HM

ISSUED TO
Shenzhen Unique Scales Co., Ltd

3rd and 6th FL., Building A, Gaoqiao community, No.22 Huanping Road
, Pingdi Street, Longgang District 518117, ShenZhen, China.



Tested by: Shang Dandan
Shang Dandan
(Engineer)

Date: Dec. 18, 2018
BALUN

Approved by: Wei Yanguan
Wei Yanguan
(Chief Engineer)

Date: Dec. 19, 2018

Report No: BL-SZ18C0268-901

EUT Name: XMTZC04HM

Model Name: XMTZC04HM

Brand Name: Mi

Test Standard: IEEE149-1979

Maximum: Gain: 1.79 (dBi)

Efficiency: 64%

Test Date: Dec. 17, 2018

Date of Issue: Dec. 19, 2018

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Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Dec. 19, 2018</u>	<u>Initial Issue</u>

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1 Administrative Data (GENERAL INFORMATION)

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L6791. The laboratory is a testing organization accredited by China Metrology Accreditation (CMA). The accreditation certificate number is 2017192290Z.
Description	All measurement facilities used to collect the measurement data are located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China 518055

1.3 Laboratory Condition

Ambient Temperature	19°C to 25°C
Ambient Relative Humidity	45% to 55%
Ambient Pressure	100 kPa to 102 kPa

1.4 Announce

- (1) The test report reference to the report template version v2.2.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without

prior written approval from the laboratory.

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Shenzhen Unique Scales Co., Ltd
Address	3rd and 6th FL., Building A, Gaoqiao community, No.22 Huanping Road, Pingdi Street, Longgang District 518117, ShenZhen, China.
Contact Person	He huiying
Telephone Number	15323447236
E-mail Address	dcc@lefu.cc

2.2 Manufacturer Information

Manufacturer	Shenzhen Unique Scales Co., Ltd
Address	3rd and 6th FL., Building A, Gaoqiao community, No.22 Huanping Road, Pingdi Street, Longgang District 518117, ShenZhen, China.

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	XMTZC04HM
Model Name Under Test	XMTZC04HM
Antenna Type	PCB Antenna
Dimensions	25mm x 6mm

2.5 Ancillary Equipment

N/A

2.6 Technical Information

Frequency Range	2400MHz~ 2480MHz
Test Frequencies	2400MHz, 2402MHz, 2404MHz, 2406MHz, 2408MHz, 2410MHz, 2412MHz, 2414MHz, 2416MHz, 2418MHz, 2420MHz, 2422MHz, 2424MHz, 2426MHz, 2428MHz, 2430MHz, 2432MHz, 2434MHz, 2436MHz, 2438MHz, 2440MHz, 2442MHz, 2444MHz, 2446MHz, 2448MHz, 2450MHz, 2452MHz, 2454MHz, 2456MHz, 2458MHz, 2460MHz, 2462MHz, 2464MHz, 2466MHz, 2468MHz, 2470MHz, 2472MHz, 2474MHz, 2476MHz, 2478MHz, 2480MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	IEEE149-1979	IEEE Standard Test Procedures for Antennas

3.2 Test Verdict

Report Section	Description	Remark
ANNEX A.1	Gain and Efficiency	--
ANNEX A.2	Return Loss	--
ANNEX A.3	Input impedance	--
ANNEX A.4	VSWR	--
ANNEX B	Radiation Pattern	--

3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Item	Uncertainty
VSWR(S11)	± 0.2
Gain	$\pm 0.5\text{dB}$

4 GENERAL TEST CONFIGURATIONS

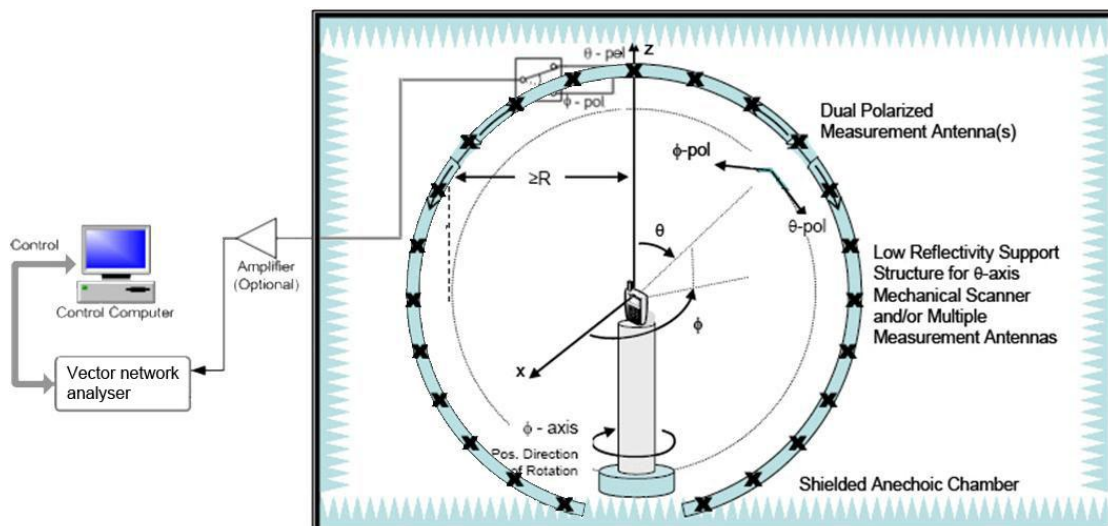
4.1 Test Condition

Environment Parameter	Selected Values During Tests			
	Ambient Pressure(KPa)	Temperature(°C)	Voltage	Relative Humidity (%)
Normal Temperature, Normal Voltage (NTNV)	100 to 102	19 to 25	N/A	45 to 55

4.2 Test Equipment List

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Vector Network Analyzer	Agilent	E5071C	MY46103472	2018.03.14	2019.03.13
5*5*5 Full Anechoic Chamber	SATIMO	5*5*5	CN-1307-555	2016.09.28	2019.09.27
SG24 Multi-probe Antenna Measurement System	SATIMO	SG24-L	1101855-0001	2018.06.22	2020.06.21

4.3 Test Setup



ANNEX A TEST RESULTS

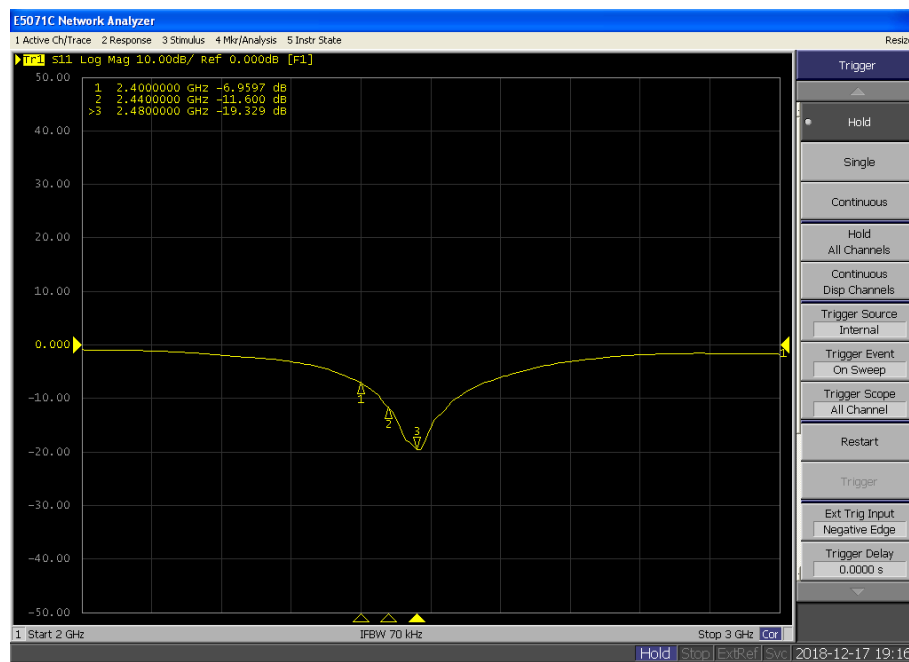
A.1 Gain and Efficiency

Frequency	Gain (dBi)	Efficiency (%)
2400MHz	0.10	44
2402MHz	0.17	45
2404MHz	0.20	45
2406MHz	0.32	46
2408MHz	0.39	46
2410MHz	0.49	47
2412MHz	0.55	48
2414MHz	0.61	48
2416MHz	0.87	50
2418MHz	0.94	51
2420MHz	0.99	52
2422MHz	0.98	52
2424MHz	0.97	53
2426MHz	1.10	55
2428MHz	1.10	55
2430MHz	1.05	55
2432MHz	1.12	56
2434MHz	1.20	57
2436MHz	1.20	57
2438MHz	1.23	57
2440MHz	1.25	57
2442MHz	1.28	58
2444MHz	1.28	59
2446MHz	1.23	59
2448MHz	1.23	59
2450MHz	1.24	60
2452MHz	1.22	61
2454MHz	1.26	61
2456MHz	1.29	61
2458MHz	1.35	62
2460MHz	1.40	62
2462MHz	1.41	62
2464MHz	1.43	63
2466MHz	1.55	63
2468MHz	1.58	64
2470MHz	1.59	64
2472MHz	1.63	64
2474MHz	1.68	64
2476MHz	1.73	64

2478MHz	1.74	64
2480MHz	1.79	64

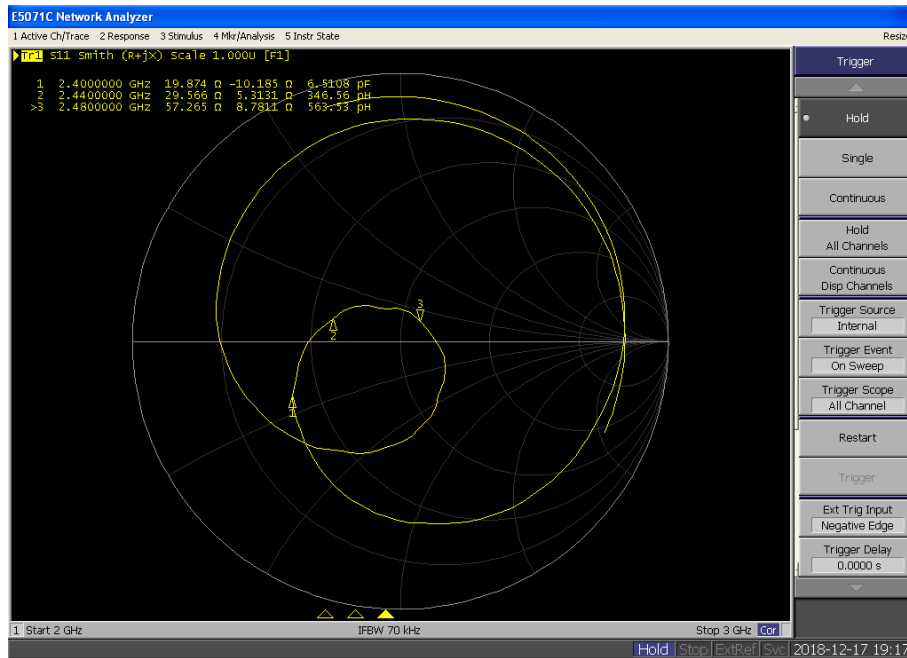
A.2 Return Loss

Frequency	Return Loss(dB)
2400MHz	-6.96
2402MHz	-11.60
2404MHz	-19.33



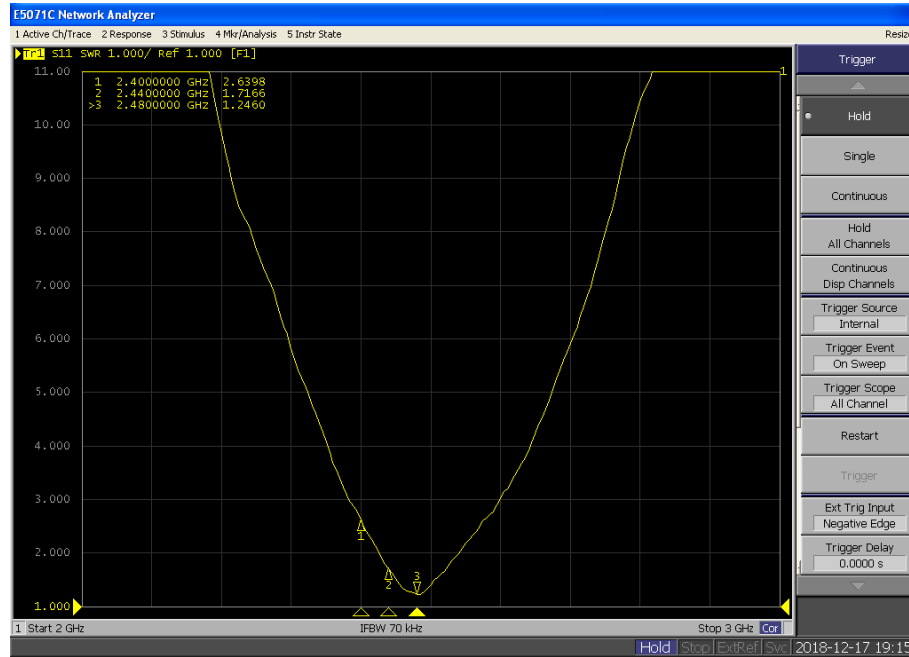
A.3 Input Impedance

Frequency	Input impedance (Ω)
2400MHz	19.87
2402MHz	29.57
2404MHz	57.27



A.4 SWR

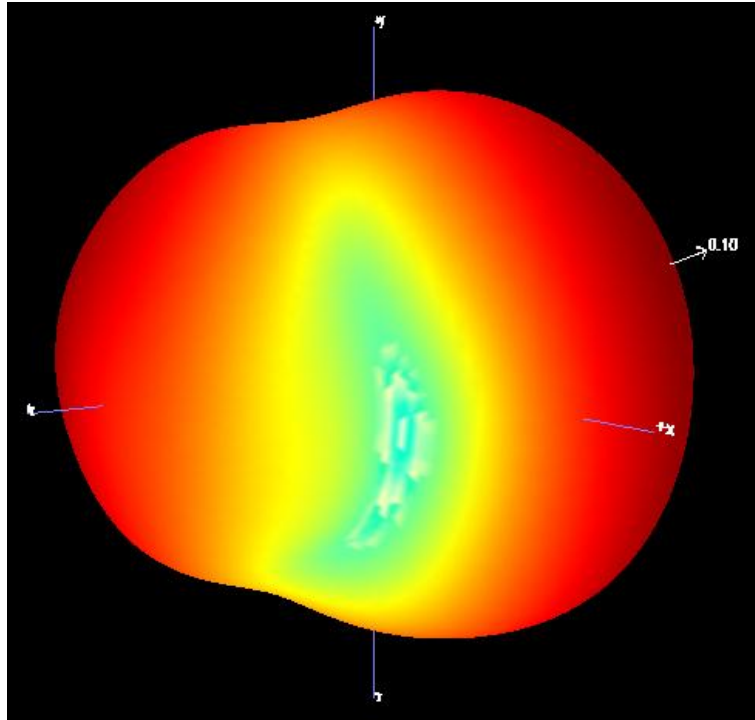
Frequency	SWR
2400MHz	2.64
2402MHz	1.72
2404MHz	1.25



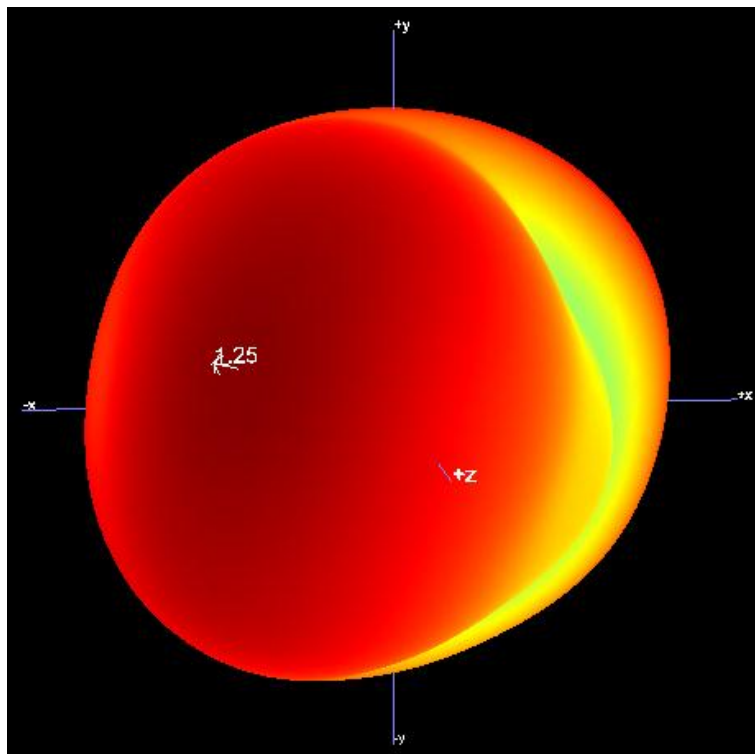
ANNEX B RADIATION PATTERN

B.1 3D Pattern

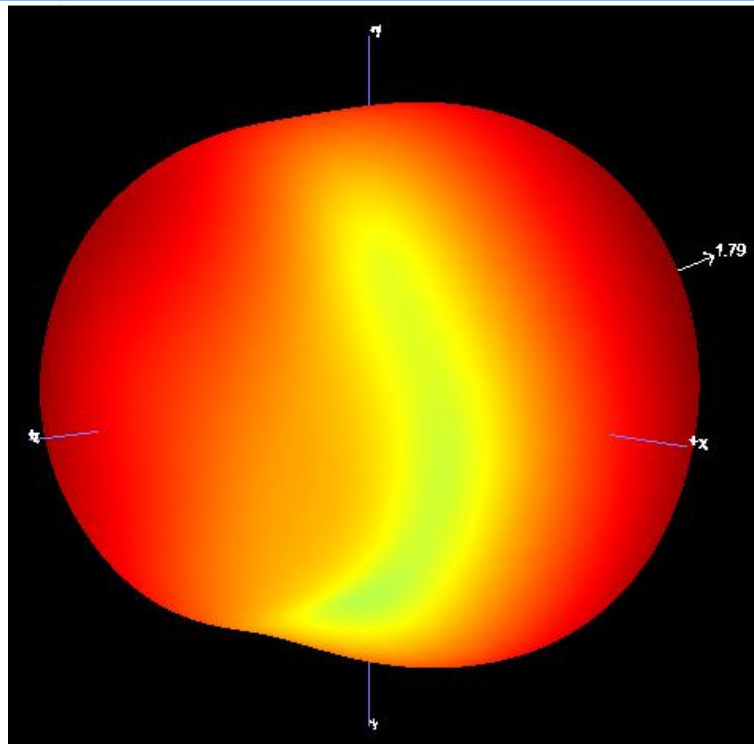
B1.1 3D Pattern for 2400MHz



B1.2 3D Pattern for 2440MHz

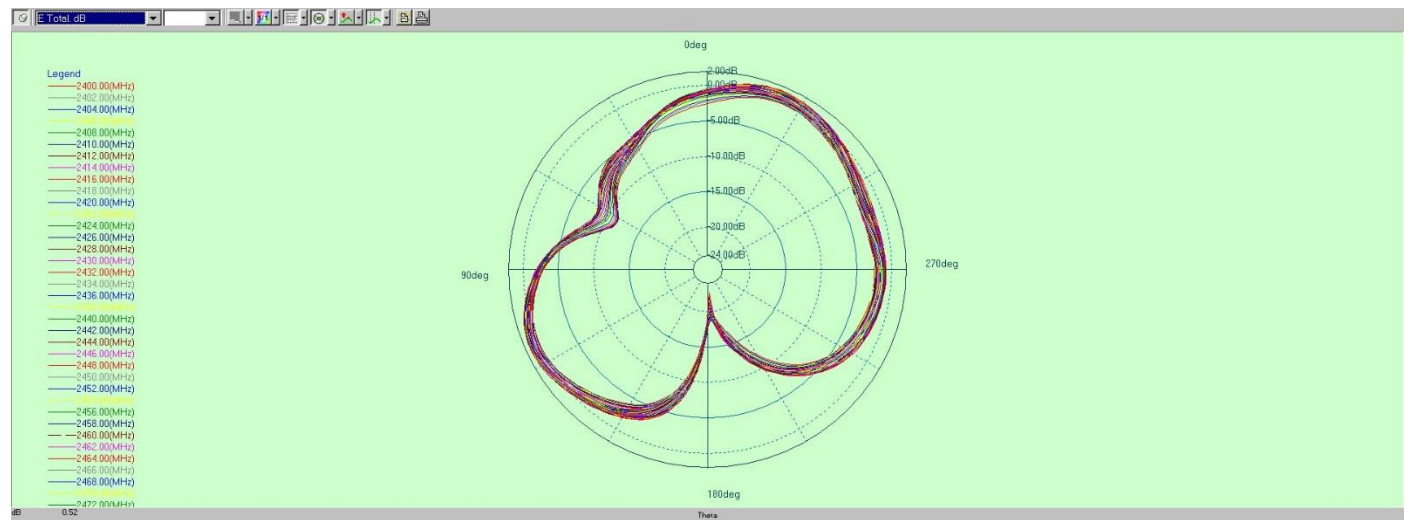


B1.3 3D Pattern for 2480MHz

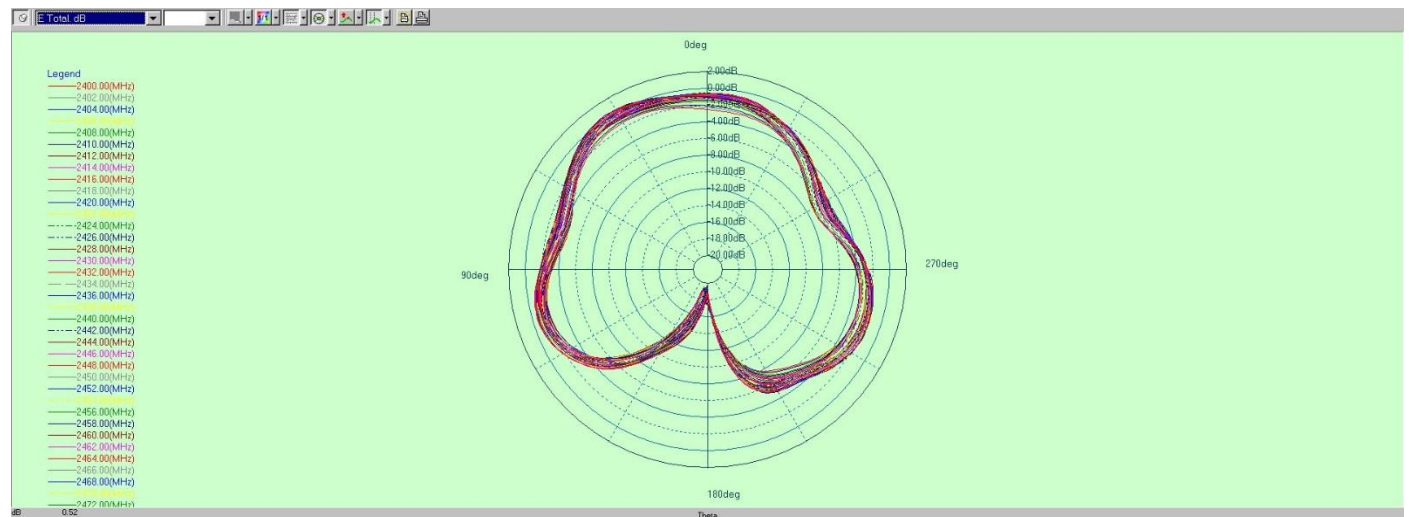


B.2 1D Radiation Pattern

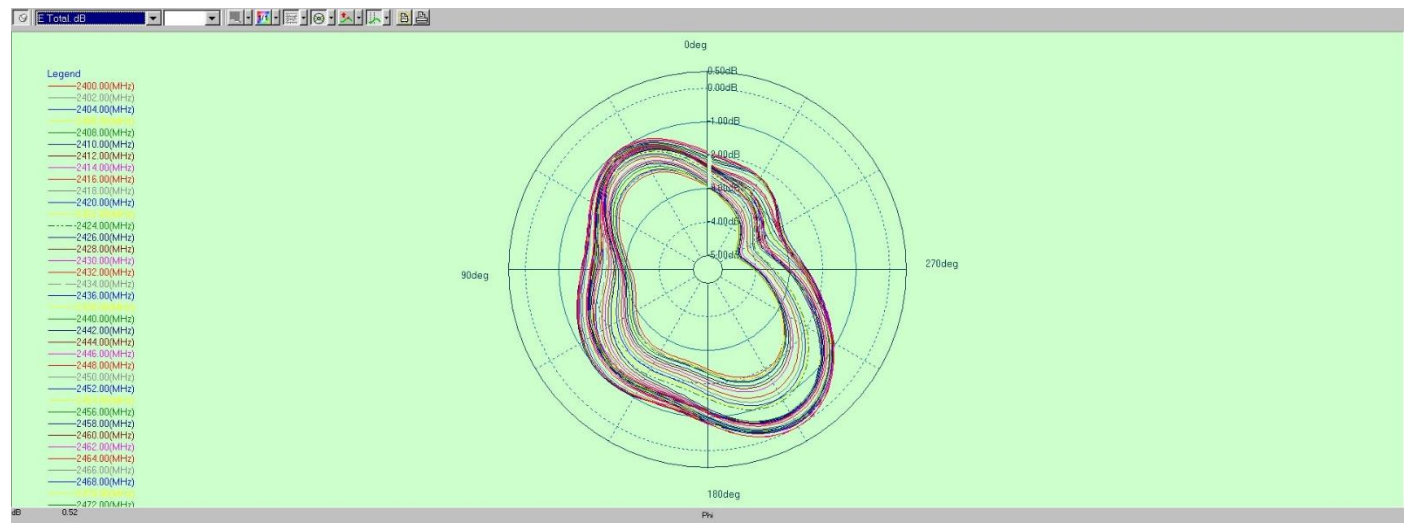
B2.1 PHI=0



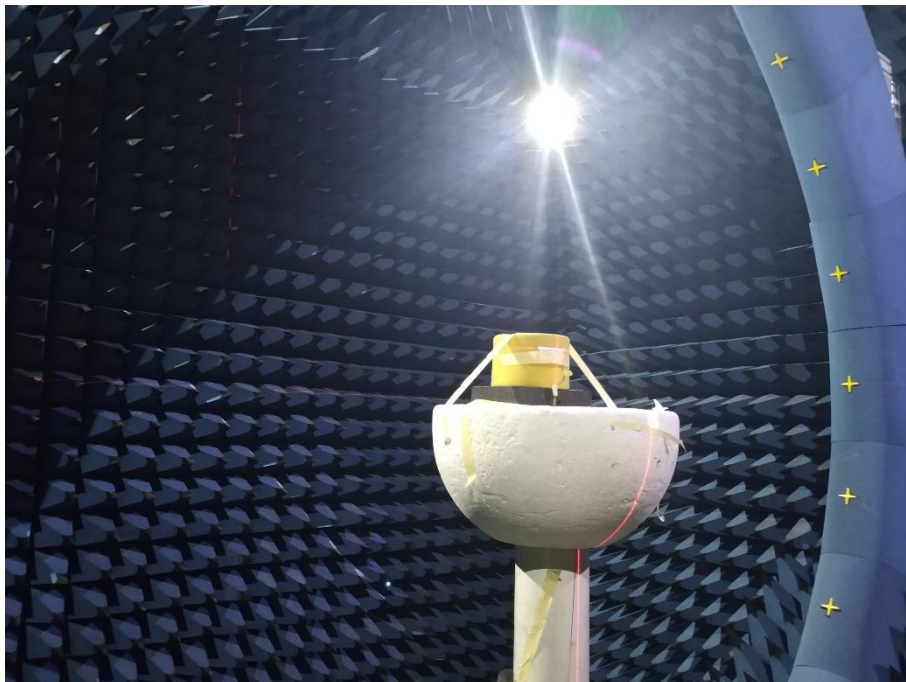
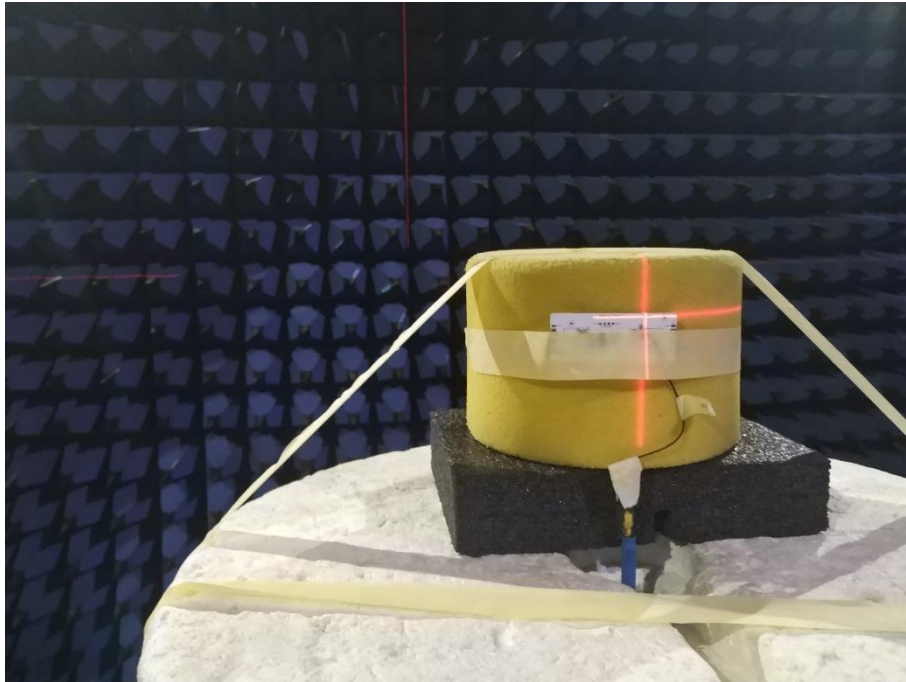
B2.2 PHI=90

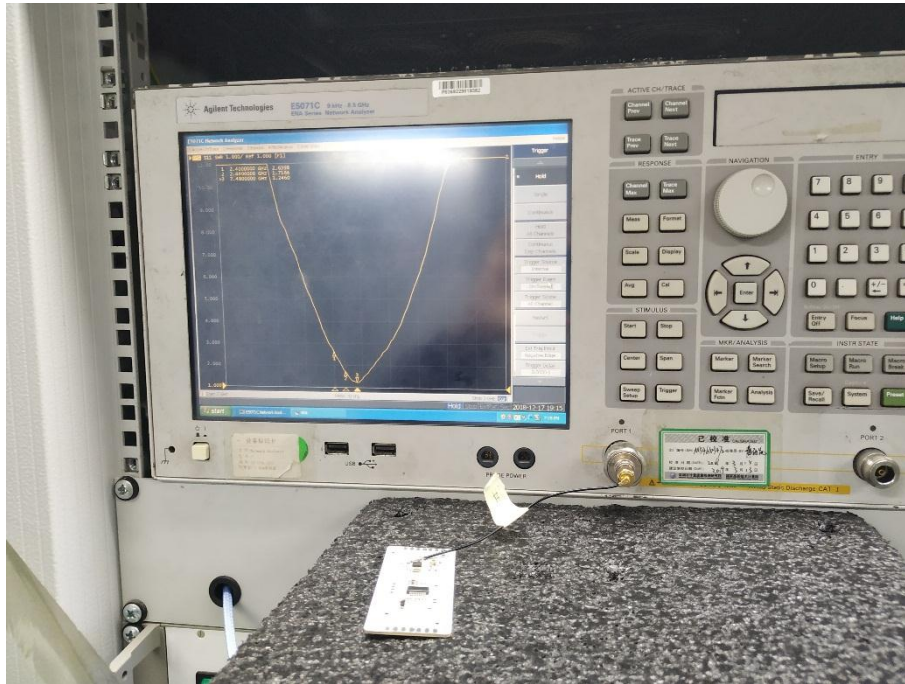


B2.3 THETA=90

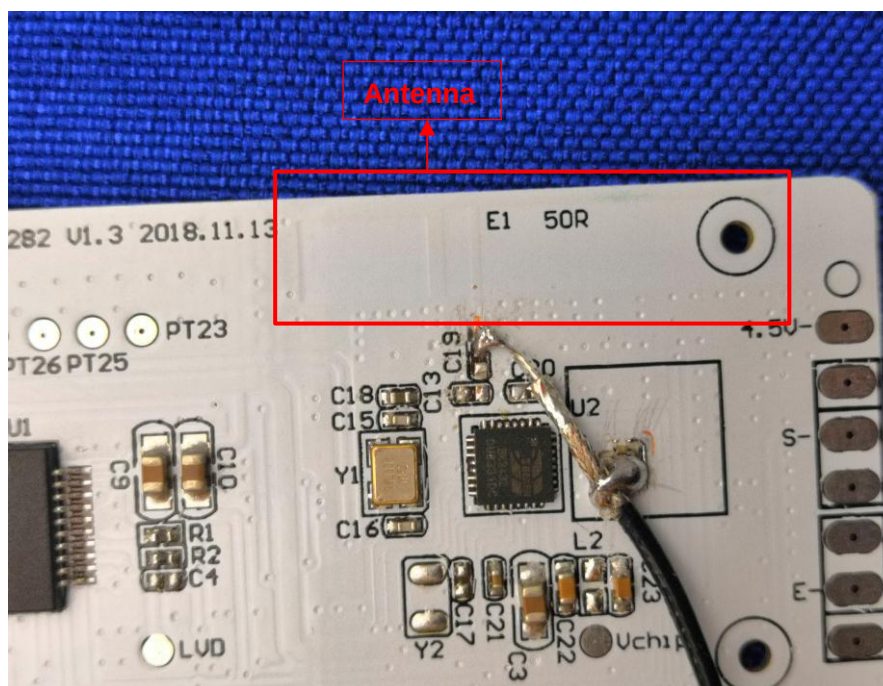
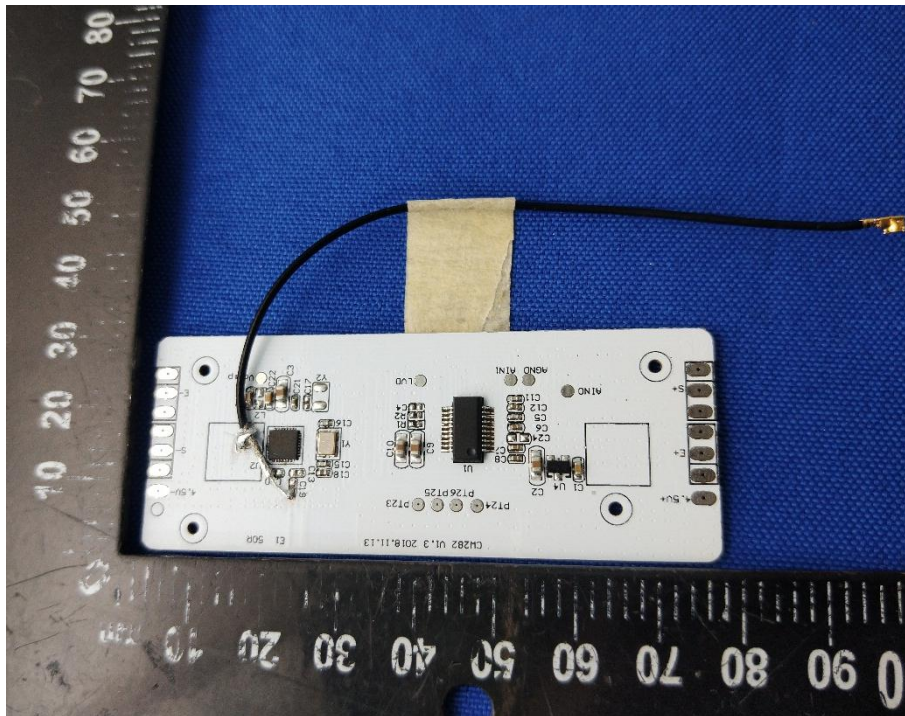


ANNEX C TEST SETUP PHOTO





ANNEX D EUT PHOTO



--END OF REPORT--